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Form PTO-1449 (REV. 1/06)	US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 129616	APPLICATION NO. 10/594,963
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.	
		FILING DATE November 14, 2006	

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	1	5,825,043	10/20/1998	SUWA
	2	4,346,164	08/24/1982	TABARELLI et al.
	3	4,480,910	11/06/1984	TAKANASHI et al.
	4	5,610,683	03/11/1997	TAKAHASHI
	5	5,715,039	02/03/1998	FUKUDA et al.
	6	2004/0165159 A1	08/26/2004	LOF et al.
	7	6,341,007	01/22/2002	NISHI et al.
	8	6,400,441	06/04/2002	NISHI et al.
	9	6,549,269	04/15/2003	NISHI et al.
	10	6,590,634	07/08/2003	NISHI et al.
	11	5,969,441	10/19/1999	LOOPSTRA et al.
	12	6,208,407	03/27/2001	LOOPSTRA

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	13	JP A 2005-045232	02/17/2005	JAPAN	X	X
	14	JP A 2005-012194	01/13/2005	JAPAN	X	X
	15	WO 2004/053953 A1	06/24/2004	JAPAN	X	
	16	JP A 2005-302880	10/27/2005	JAPAN	X	X
	17	JP A 2005-191557	07/14/2005	JAPAN	X	X
	18	JP A 4-305915	10/28/1992	JAPAN	X	X
	19	JP A 4-305917	10/28/1992	JAPAN	X	X
	20	JP A 10-303114	11/13/1998	JAPAN	X	X
	21	JP A 10-340846	12/22/1998	JAPAN	X	X
	22	JP A 11-176727	07/02/1999	JAPAN	X	X
	23	JP A 2000-58436	02/25/2000	JAPAN	X	X

EXAMINER

/Mesfin Asfaw/

DATE CONSIDERED  
02/06/2009

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: March 5, 2007

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /M.A./

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 129616		APPLICATION NO. 10/594,963	
INFORMATION DISCLOSURE STATEMENT							
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FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	24	JP A 63-157419	06/30/1988	JAPAN	X	X	
	25	JP A 58-202448	11/25/1983	JAPAN	X	X	
	26	JP A 62-65326	03/24/1987	JAPAN	X	X	
	27	JP A 59-19912	02/01/1984	JAPAN	X	X	
	28	JP A 5-62877	03/12/1993	JAPAN	X	X	
	29	JP A 6-124873	05/06/1994	JAPAN	X	X	
	30	JP A 7-220990	08/18/1995	JAPAN	X	X	
	31	JP A 8-316125	11/29/1996	JAPAN	X	X	
	32	WO 99/49504 A1	09/30/1999	WIPO	X	X	
	33	WO 2004/019128 A2	03/04/2004	WIPO			
	34	DD 221 563 A1	04/24/1985	GERMANY	X	X	
	35	DD 224 448 A1	07/03/1985	GERMANY	X	X	
	36	EP 1 420 298 A2	05/19/2004	EUROPE			
	37	WO 2004/055803 A1	07/001/2004	WIPO			
	38	WO 2004/057590 A1	07/08/2004	WIPO			
	39	WO 2005/029559 A1	03/31/2005	WIPO	X		
	40	WO 2004/019128 A2	03/04/2004	WIPO			
	41	WO 01/35168 A1	05/17/2001	WIPO			
	42	JP A 10-163099	06/19/1998	JAPAN	X	X	
	43	JP A 10-214783	08/11/1998	JAPAN	X	X	
	44	JP A 11-135400	05/21/1999	JAPAN	X	X	
	45	JP A 2000-505958	05/16/2000	JAPAN	X	X	
	46	JP A 2000-164504	06/16/2000	JAPAN	X	X	
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